

Lucas Signatone Corp.

393-J Tomkins Ct. • Gilroy, CA 95020 U.S.A. • Phone: (408) 848-2851 • Fax: (408) 848-5763
www.signatone.com e-mail: sales@signatone.com

Resistivity Standards (RS) span 4 decades and are designed for calibrating both contact and non-contact resistivity measuring instruments. The standard is created by sawing a doped single crystalline ingot into wafers, lapping and chemically cleaning them to VLSI Standards' specifications.

Product Description

The silicon is p-type (Boron) doped to nominal resistivity values, from 0.002 ohm.cm to 75 ohm.cm as available on the 3" model. For enhanced measurement on contact probes, the wafers are lapped and chemically polished. The increased surface roughness allows cleaner penetration through the native oxide layer and better contact.

Each wafer is certified at its center, NIST Traceable for accuracy. Certificates of Calibration are provided with each standard and report the resistivity, sheet resistance and thickness measurement values with calculated uncertainties.

Product Specifications

Wafer Size	Resistivity [Ohm.cm]	Sheet resistance [Ohms/Sq.]	Thickness	Electrical Property (type)	Signatone Part Number
76.2 mm	0.002	0.04	508 µm	p	SRS3-0.002
76.2 mm	0.01	0.2	508 µm	p	SRS3-0.01
76.2 mm	0.03	0.6	508 µm	p	SRS3-0.03
76.2 mm	0.1	2	508 µm	p	SRS3-0.1
76.2 mm	0.3	6	508 µm	p	SRS3-0.3
76.2 mm	0.9	18	508 µm	p	SRS3-0.9
76.2 mm	3	60	508 µm	p	SRS3-3.0
76.2 mm	10	200	508 µm	p	SRS3-10
76.2 mm	30	600	508 µm	n	SRS3-30
76.2 mm	57	1100	508 µm	n	SRS3-57
76.2 mm	75	1500	508 µm	n	SRS3-75

Please contact your local Lucas Signatone Corporation sales representative or our head quarters for pricing and delivery.

sales@signatone.com